

# DMIP - Exercise:

## *Defect Pixel Interpolation*

Yan Xia, Marco Bögel  
Pattern Recognition Lab (CS 5)



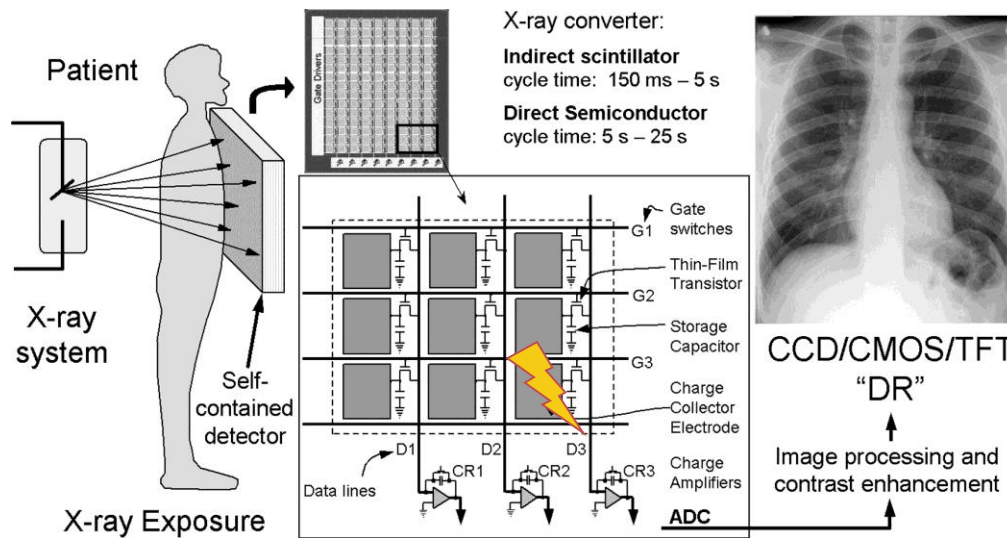
FRIEDRICH-ALEXANDER  
UNIVERSITÄT  
ERLANGEN-NÜRNBERG

TECHNISCHE FAKULTÄT

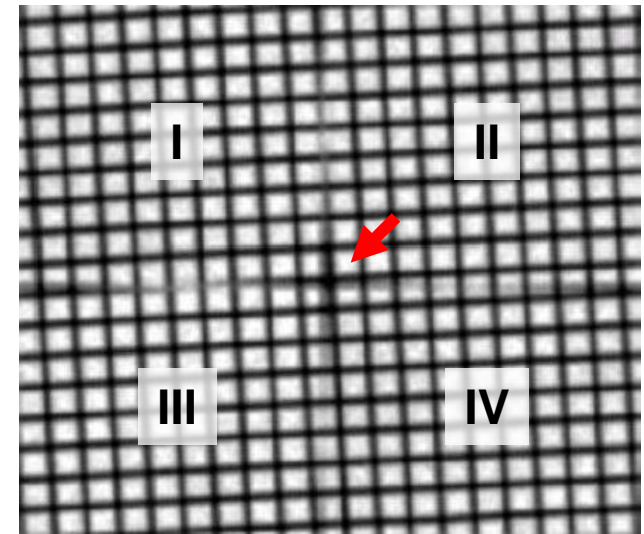
# Flat Panel Detectors

## Defect Pixels in Flat Panel Detectors

- Defect pixels are caused by defect detector cells.
- Small detectors are composed to generate a large one, which leads to butting cross effects.



Artifacts due to inactive pixels or rows



Butting Cross Artifact

Image taken from: Samei E et al. Radiographics 2004;24:313-334

Image taken from: Lecture DMIP (Maier, Hornegger)

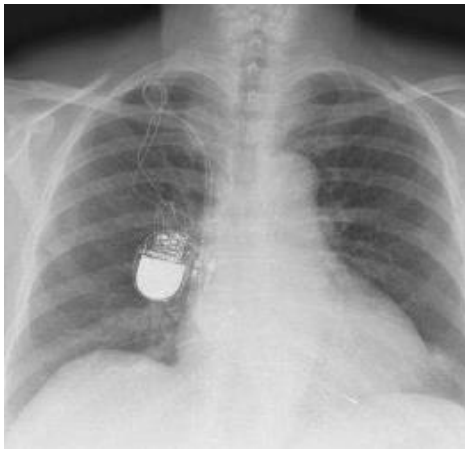
# Flat Panel Detectors

## Defect Pixels in Flat Panel Detectors

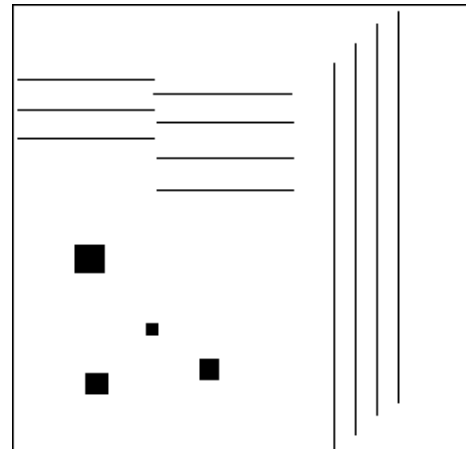
- Let  $f_{i,j}$  denote the intensity value at grid point  $(i,j)$  of the **ideal image**  $f$  that has no defect pixels.
- Let  $w_{i,j}$  denote the indicator value at  $(i,j)$  where  $w$  is **mask image** that indicates defect and uncorrupted pixels:

$$w_{i,j} = \begin{cases} 0 & \text{if pixel is defect} \\ 1 & \text{otherwise} \end{cases}$$

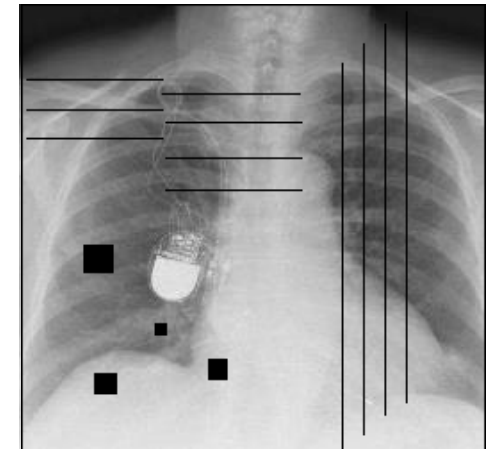
- Let  $g_{i,j}$  denote the intensity value at grid point  $(i,j)$  of the **observed image**  $g$  that is acquired with the flat panel detector that has defect pixels.



Ideal image  $f$



Mask image  $w$



Observed image  $g$

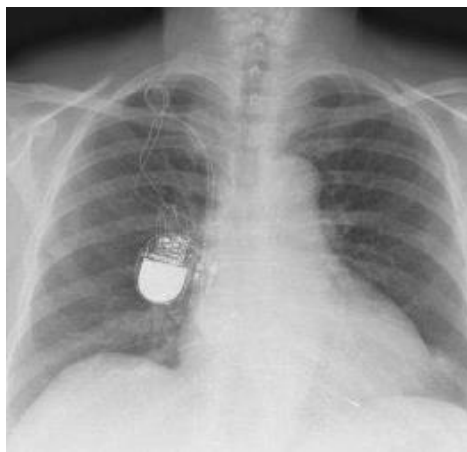
# Flat Panel Detectors

## Defect Pixels in Flat Panel Detectors

- Let  $f_{i,j}$  denote the intensity value at grid point  $(i,j)$  of the **ideal image**  $f$  that has no defect pixels.
- Let  $w_{i,j}$  denote the indicator value at  $(i,j)$  where  $w$  is **mask image** that indicates defect and uncorrupted pixels:

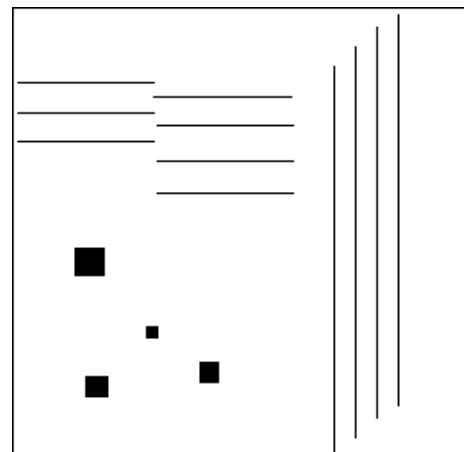
$$w_{i,j} = \begin{cases} 0 & \text{if pixel is defect} \\ 1 & \text{otherwise} \end{cases}$$

- Let  $g_{i,j}$  denote the intensity value at grid point  $(i,j)$  of the **observed image**  $g$  that is acquired with the flat panel detector that has defect pixels.



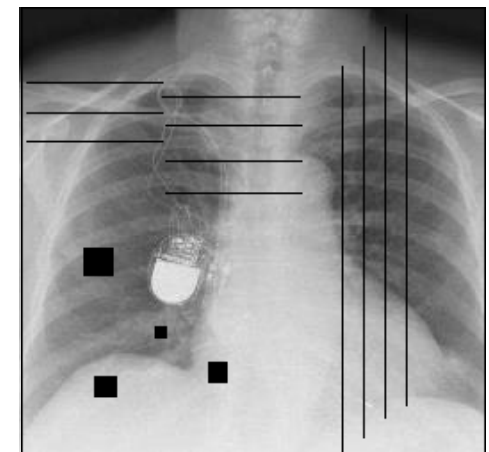
Ideal image  $f$

•



Mask image  $w$

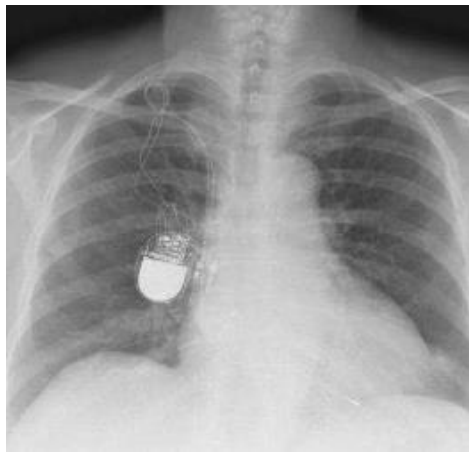
=



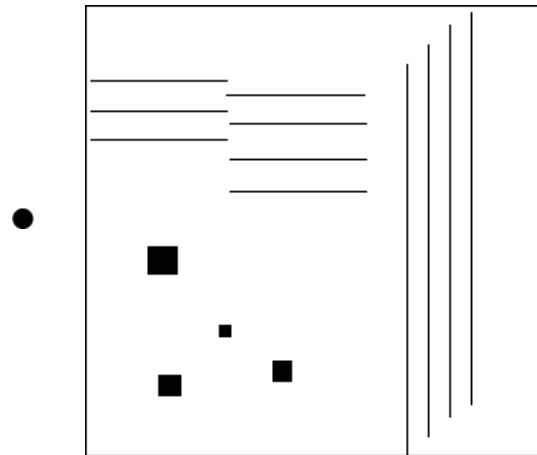
Observed image  $g$

# Flat Panel Detectors

## Defect Pixels in Flat Panel Detectors

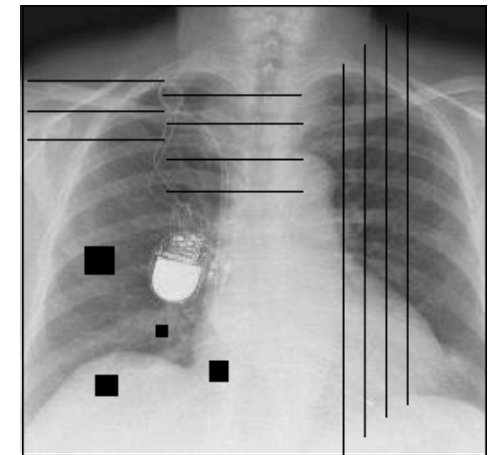


Ideal image  $f$



Mask image  $w$

=



Observed image  $g$

- Defect pixel problem:  $f(n) \cdot w(n) = g(n)$
- Goal: Find  $f(n)$ , given the observed image  $g(n)$  and the defect mask  $w(n)$

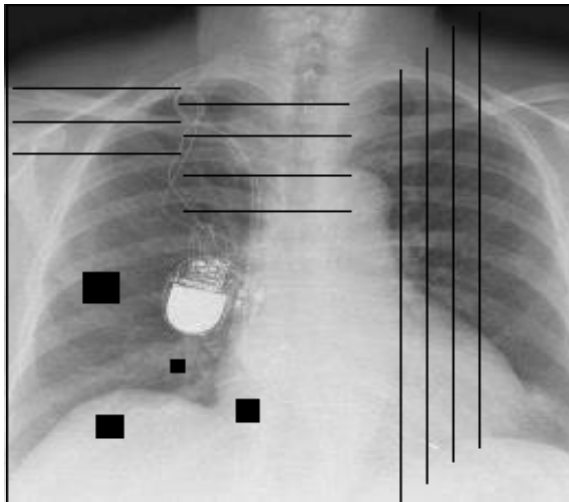


# Defect Pixel Correction

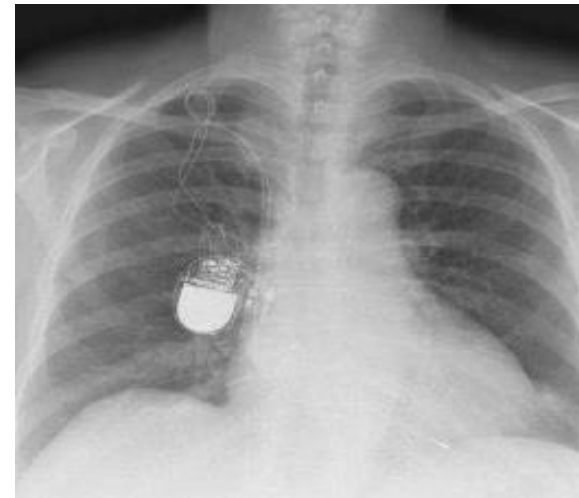
# Defect Pixel Correction

## Problem Statement

- Restore the **ideal image** based on the **observed image** and the known defect **pixel mask**.
- Defect pixel correction:
  - *Spatial Domain:* Interpolation
  - *Frequency Domain:* Band Limitation
  - *Frequency Domain:* Iterative Deconvolution



Observed image  $g$

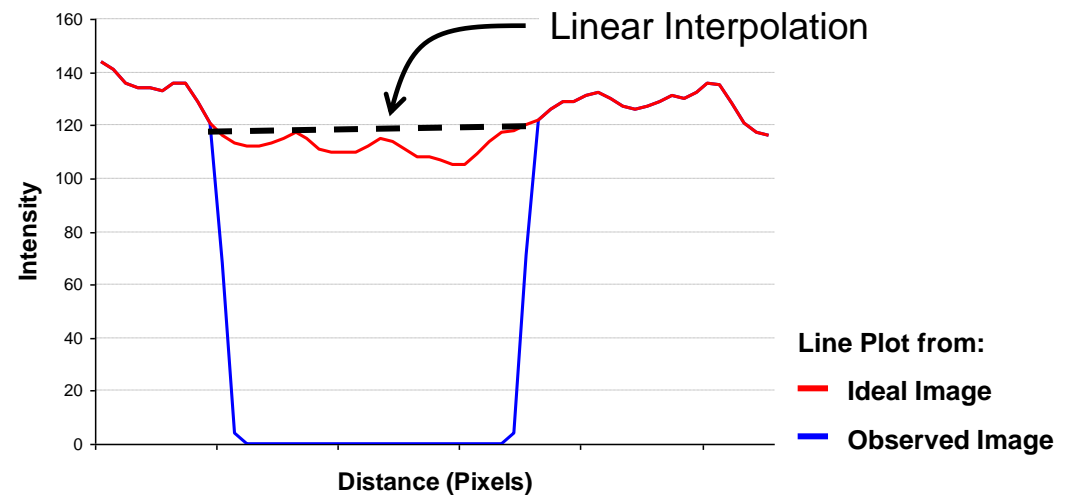
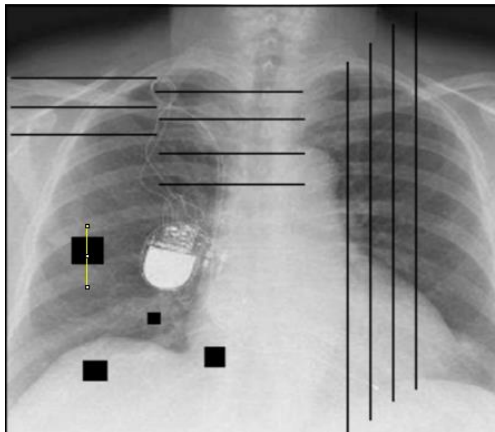


Ideal image  $f$

# Defect Pixel Correction

## Defect Pixel Correction by Spatial Interpolation

- Interpolate between active pixels to recover the inactive ones:
  - Bilinear interpolation
  - Median
- **However, this is only suitable for small defect areas!**







# Defect Pixel Correction

## Fourier Transform Revisited

- Convolution theorem
- Symmetry property of Fourier transform of real signals



# Defect Pixel Correction

## Fourier Transform Revisited

- **Convolution theorem**

$$\begin{aligned} FT(f \star h)(\xi) &= \sum_{n=0}^{N-1} \sum_{k=0}^{N-1} f(k)h(n-k)e^{\frac{-2\pi in\xi}{N}} \\ &= \sum_{k=0}^{N-1} f(k) \sum_{n=0}^{N-1} h(n-k)e^{\frac{-2\pi in\xi}{N}} \\ &= \sum_{k=0}^{N-1} f(k)e^{\frac{-2\pi ik\xi}{N}} H(\xi) = F(\xi)H(\xi) = G(\xi) \end{aligned}$$

The **convolution** of two signals in the **time domain**, corresponds to a **multiplication** in the **frequency domain**.

- **Symmetry property of Fourier transform of real signals**



# Defect Pixel Correction

## Fourier Transform Revisited

- Convolution theorem
- Symmetry property of Fourier transform of real signals

If  $f(n)$  is a real valued discrete signal of length  $N$ , the Fourier transform  $F(\xi)$  fulfills the symmetry property:

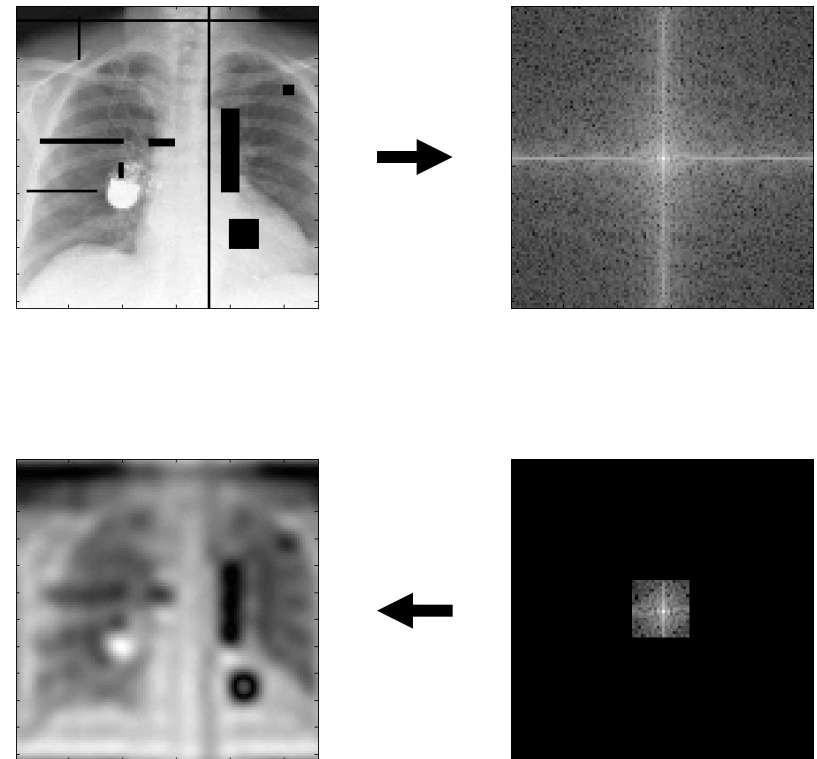
$$F(\xi) = F^*(N - \xi)$$

where “\*“ denotes the conjugate complex.

# Defect Pixel Correction

## Iterative Band Limitation

1. **Fourier transform**
2. **Cut off high frequencies**
3. **Inverse Fourier transform**
4. **Replace only defect areas**
5. **Repeat from 1.**

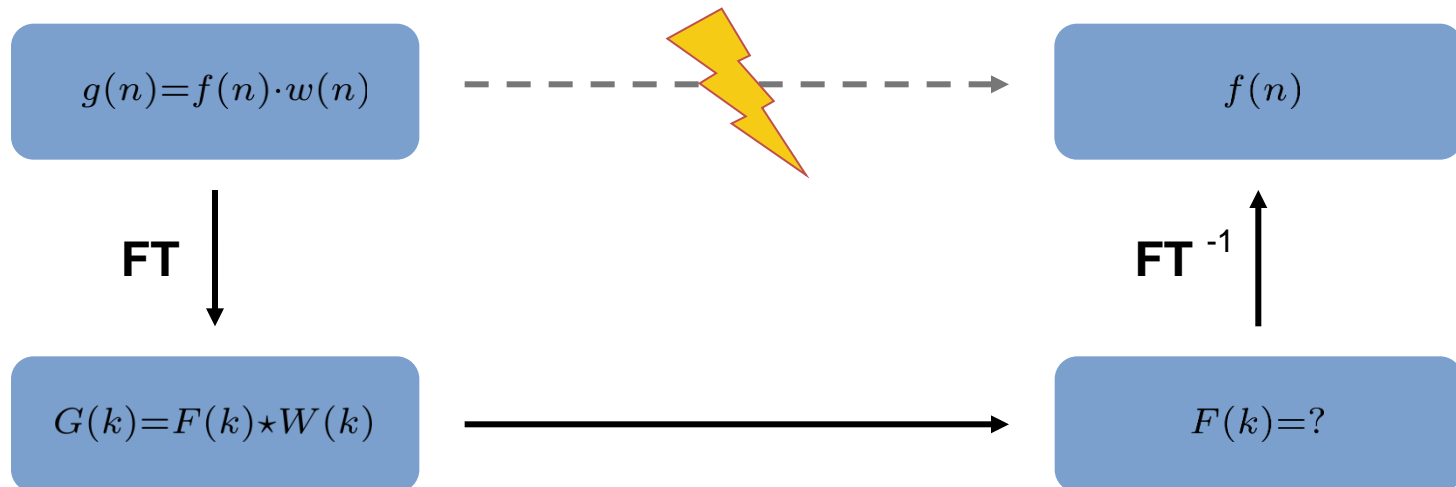




# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- Application of Fourier convolution theorem:



$$G(k) = \frac{1}{N} F(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} F(l) \cdot W(k-l), \quad 0 \leq n, k < N$$



# Defect Pixel Correction

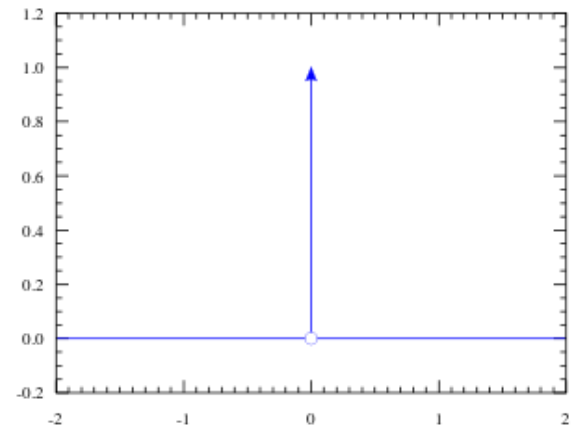
## Defect Pixel Correction by Symmetry Properties

- **Application of Fourier symmetry properties:**
- Use Dirac's  $\delta$ -function to select a line pair  $F(s)$  and  $F(N-s)$ :

$$\hat{F}(k) = \hat{F}(s)\delta(k - s) + \hat{F}(N - s)\delta(k - N + s)$$

where  $\hat{F}$  denotes an estimate of  $F$ , and  $\delta$ -function is defined by:

$$\delta(n) = \begin{cases} 1 & \text{if } n = 0 \\ 0 & \text{otherwise} \end{cases}$$



Dirac  $\delta$ -function

Image taken from: Wikipedia



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$





# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\hat{G}(k) = \frac{1}{N} \left( \hat{F}(s)W(k-s) + \hat{F}(N-s)W(k-(N-s)) \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\begin{aligned} \hat{G}(k) &= \frac{1}{N} \left( \hat{F}(s)W(k-s) + \underbrace{\hat{F}(N-s)W(k-(N-s))}_{= \hat{F}^*(s)} \right) \\ &= \hat{F}^*(s) \end{aligned}$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\hat{G}(k) = \frac{1}{N} \left( \hat{F}(s)W(k-s) + \hat{F}^*(s)W(k-(N-s)) \right)$$

- We are only interested in  $\hat{G}(k)$  at position  $k = s$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\hat{G}(k) = \frac{1}{N} \left( \hat{F}(s)W(k-s) + \hat{F}^*(s)W(k-(N-s)) \right)$$

- We are only interested in  $\hat{G}(k)$  at position  $k = s$

$$\hat{G}(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s-N) \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\hat{G}(k) = \frac{1}{N} \left( \hat{F}(s)W(k-s) + \hat{F}^*(s)W(k-(N-s)) \right)$$

- We are only interested in  $\hat{G}(k)$  at position  $k = s$

$$\hat{G}(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s - N) \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- After frequency selection, we convolve with the mask

$$\hat{G}(k) = \frac{1}{N} \hat{F}(k) \star W(k) = \frac{1}{N} \sum_{l=0}^{N-1} \hat{F}(l) \cdot W(k-l)$$

- $\hat{F}(l)$  is only non-zero if  $l = s \vee l = N - s$

$$\hat{G}(k) = \frac{1}{N} \left( \hat{F}(s)W(k-s) + \hat{F}^*(s)W(k-(N-s)) \right)$$

- We are only interested in  $\hat{G}(k)$  at position  $k = s$

$$\hat{G}(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s) \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- **Application of Fourier symmetry properties:**

Select a line pair  $G(s)$  and  $G(N-s)$  of the Fourier transform of the observed image. The observed image is described by a convolution of the ideal image and the known defect pixel mask:

$$G(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s) \right)$$

- And for the conjugate complex:

$$G^*(s) = \frac{1}{N} \left( \hat{F}^*(s)W^*(0) + \hat{F}(s)W^*(2s) \right)$$

- Using these two equations, we can compute:

$$\hat{F}(s) = N \frac{G(s)W^*(0) - G^*(s)W(2s)}{|W(0)|^2 - |W(2s)|^2}$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- Special case without symmetry property (for  $s=0$  and  $s = N/2$ )

$$G(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s) \right)$$

$$G^*(s) = \frac{1}{N} \left( \hat{F}^*(s)W^*(0) + \hat{F}(s)W^*(2s) \right)$$





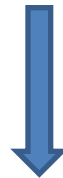
# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- Special case without symmetry property (for  $s=0$  and  $s = N/2$ )

$$G(s) = \frac{1}{N} \left( \hat{F}(s)W(0) + \hat{F}^*(s)W(2s) \right)$$

~~$$G^*(s) = \frac{1}{N} \left( \hat{F}^*(s)W^*(0) + \hat{F}(s)W^*(2s) \right)$$~~



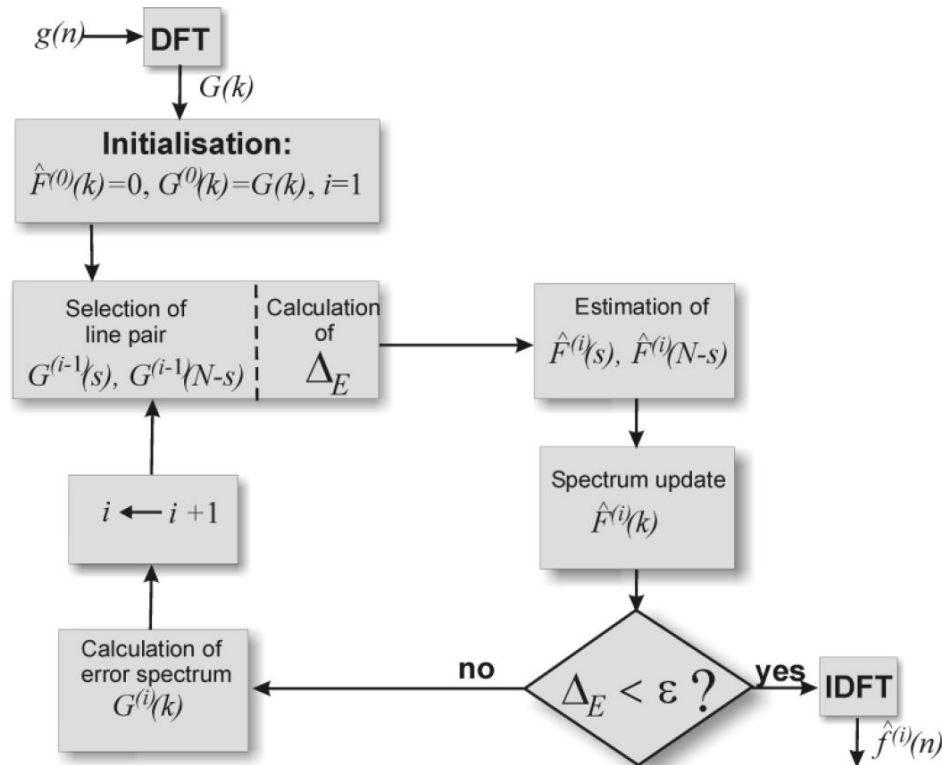
$$\hat{F}(s) = N \left( \frac{G(s)}{W(0)} \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

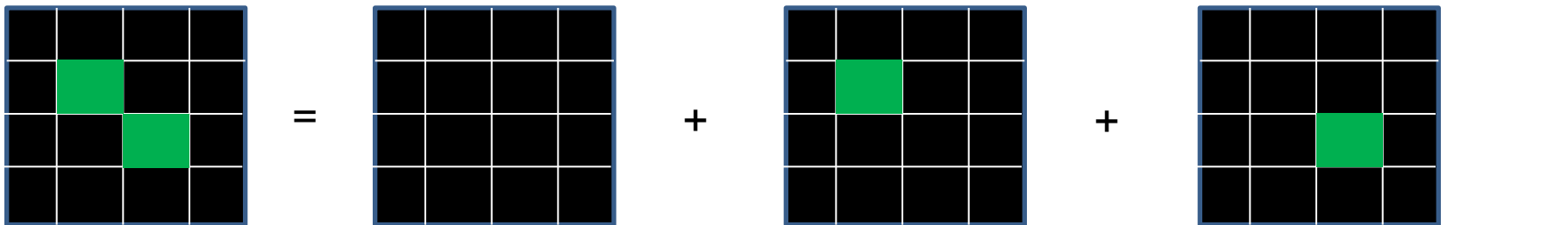
- So far only correction at line pair
  - ➔ Iterative correction of line pairs



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- So far we only found estimates for a single or a pair of selected lines
- We also need to update the global estimate of the spectrum after each linepair computation



$\hat{F}^{(1)}(k)$        $\hat{F}^{(0)}(k) = 0$        $\hat{F}(s^{(1)})$        $\hat{F}(N - s^{(1)}) = \hat{F}^*(s^{(1)})$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- How can we update the error spectrum  $G$ ?

$$G^{(i)}(k) = G^{(i-1)}(k) - \hat{G}(k) = G^{(i-1)}(k) - \frac{1}{N} \left( \hat{F}(k) * W(k) \right)$$



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- How can we update the error spectrum  $G$ ?

$$G^{(i)}(k) = G^{(i-1)}(k) - \hat{G}(k) = G^{(i-1)}(k) - \frac{1}{N} \left( \hat{F}(k) * W(k) \right)$$

- Just subtract the new estimate from the previous estimate
- Requires convolution!!! → Same complexity as FFT?
- $F(k)$  changed only at two positions → Convolution much easier to compute



# Defect Pixel Correction

## Defect Pixel Correction by Symmetry Properties

- How to select the line pairs each iteration?
- Just select the maximum of the error spectrum

$$s^{(i)} = \operatorname{argmax}_{\hat{s}^{(i)}} G^{(i)}(\hat{s}^{(i)})$$

- Detailed derivation can be found in the paper.
- It is based on Parseval's theorem.
- Approach minimizes the mean square error (MSE) in valid areas:

$$\text{MSE} = \sum_{n=0}^N (g(n) - \hat{f}(n)w(n))^2$$